

Product Summary

$V_{(BR)DSS}$	$R_{DS(on)}TYP$	I_D
100V	90mΩ@10V	8A
	100mΩ@4.5V	
-100V	230mΩ@-10V	-7A
	240mΩ@-4.5V	


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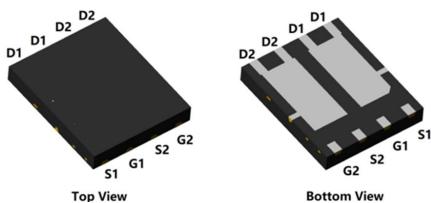
Feature

- Fast switching speed
- Surface mount package
- ROHS Compliant & Halogen-Free
- 100% Single Pulse avalanche energy Test

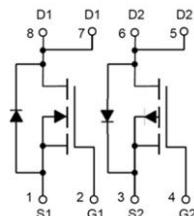
Applications

- DC-DC Converters.
- Motor Control.

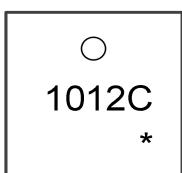
Package


PDFN5X6-8L

Circuit diagram



Marking


 1012C
 *

 :Device Code
 :Month Code

Order Information

Device	Package	Unit/Tape
SP1012CNK	PDFN5X6-8L	5000

Absolute maximum ratings (Ta=25°C,unless otherwise noted)

Parameter	Symbol	Rating		Unit
		N-Channel	P-Channel	
Drain-Source Voltage	V _{DS}	100	-100	V
Gate-Source Voltage	V _{GS}	±20	±20	V
Continuous Drain Current (Tc=25°C)	I _D	8	-7	A
Pulse Drain Current Tested	I _{DM}	32	-28	A
Single pulsed avalanche energy ¹	E _{AS}	20	49	mJ
Power Dissipation (Tc=25°C)	P _D	20		W
Thermal Resistance Junction-to-Case	R _{θJC}	6.25		°C/W
Storage Temperature Range	T _{STG}	-55 to 150		°C
Operating Junction Temperature Range	T _J	-55 to 150		°C

N-Electrical characteristics (Ta=25°C, unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	VGS=0V , ID=250uA	100	-	-	V
Drain-Source Leakage Current	I _{DSS}	VDS=80V , VGS=0V , TJ=25°C	-	-	1	uA
Gate-Source Leakage Current	I _{GSS}	VGS=±20V , VDS=0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	VGS=VDS , ID =250uA	1.0	1.8	2.5	V
Static Drain-Source On-Resistance	R _{DS(ON)}	VGS = 10V, ID = 4A	-	90	115	mΩ
		VGS = 4.5V, ID = 3A	-	100	135	
Dynamic characteristics						
Input Capacitance	C _{iss}	VDS=50V , VGS=0V , f=1MHz	-	695	-	pF
Output Capacitance	C _{oss}		-	25	-	
Reverse Transfer Capacitance	C _{rss}		-	17	-	
Total Gate Charge	Q _g	VDS=50V , VGS=10V , ID=5A	-	13.6	-	nC
Gate-Source Charge	Q _{gs}		-	2.1	-	
Gate-Drain Charge	Q _{gd}		-	1.9	-	
Switching Characteristics						
Turn-On Delay Time	T _{d(on)}	VDD=50V VGS=10V , RG=3Ω, ID=3A	-	7	-	nS
Rise Time	T _r		-	1.5	-	
Turn-Off Delay Time	T _{d(off)}		-	15.3	-	
Fall Time	T _f		-	2	-	
Diode Characteristics						
Diode Forward Voltage	V _{SD}	VGS=0V , IS=1A , TJ=25°C	-	-	1.2	V
Maximum Body-Diode Continuous Current	I _s		-	-	10	A
Reverse recover time	T _{rr}	I _s =3A, di/dt=100A/us, Tj=25°C	-	31	-	nS
Reverse recovery charge	Q _{rr}		-	23	-	nC

Note:

1.The EAS Test condition is VDD=50V,VGS =10V,L = 0.5mH, Rg=25Ω

P-Electrical characteristics (Ta=25°C, unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	VGS=0V , ID=-250uA	-100	-	-	V
Drain-Source Leakage Current	I _{DSS}	VDS=-80V , VGS=0V , TJ=25°C	-	-	-1	uA
Gate-Source Leakage Current	I _{GSS}	VGS=±20V , VDS=0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	VGS=VDS , ID =-250uA	-1.0	-1.8	-2.5	V
Static Drain-Source On-Resistance	R _{Ds(on)}	VGS =-10V, ID =-2A	-	230	290	mΩ
		VGS =-4.5V, ID =-1A	-	240	320	
Dynamic characteristics						
Input Capacitance	C _{iss}	VDS=-50V , VGS=0V , f=1MHz	-	721	-	pF
Output Capacitance	C _{oss}		-	30	-	
Reverse Transfer Capacitance	C _{rss}		-	18	-	
Total Gate Charge	Q _g	VDS=-50V , VGS=-10V , ID=-3A	-	16	-	nC
Gate-Source Charge	Q _{gs}		-	3	-	
Gate-Drain Charge	Q _{gd}		-	2.5	-	
Switching Characteristics						
Turn-On Delay Time	T _{d(on)}	VDD=-50V VGS=-10V , RG=6Ω, ID=-3A	-	9	-	nS
Rise Time	T _r		-	6.5	-	
Turn-Off Delay Time	T _{d(off)}		-	28	-	
Fall Time	T _f		-	7.5	-	
Diode Characteristics						
Diode Forward Voltage	V _{SD}	VGS=0V , IS=-1A , TJ=25°C	-	-	-1.2	V
Maximum Body-Diode Continuous Current	I _S	IS=-5A, di/dt=-100A/us, TJ=25°C	-	-	-7	A
Reverse recover time	T _{rr}		-	26.5	-	nS
Reverse recovery charge	Q _{rr}		-	31	-	nC

Note:

1.The EAS Test condition is VDD=-50V,VGS =-10V,L = 0.5mH, Rg=25Ω



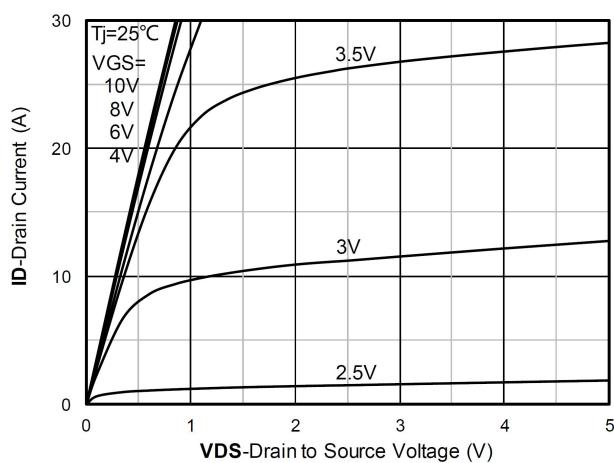
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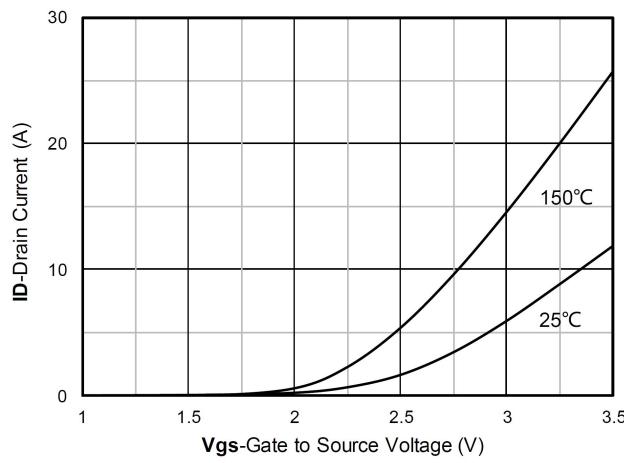
SP1012CNK

100V Complementary MOSFET

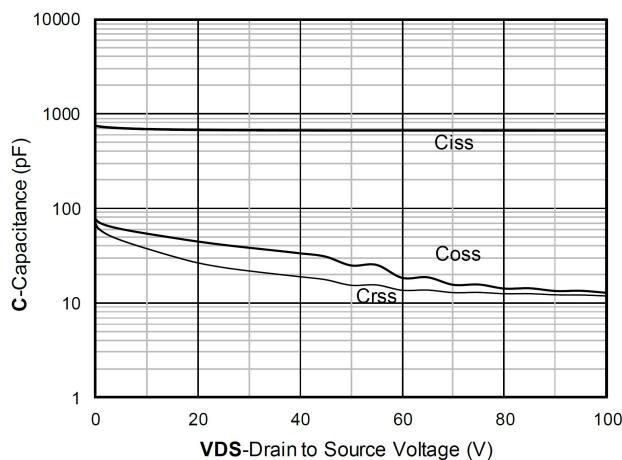
N-Channel Typical Characteristics



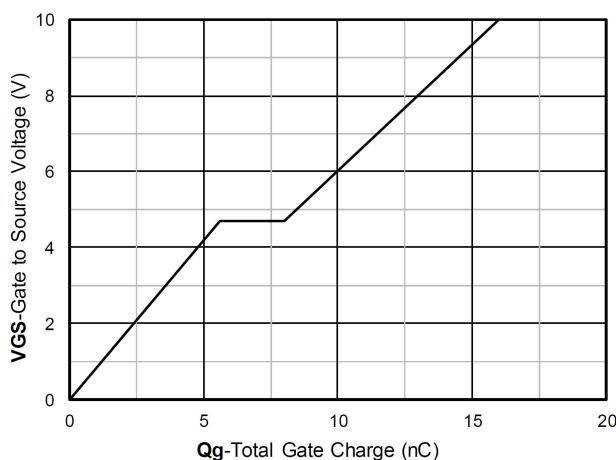
Output Characteristics



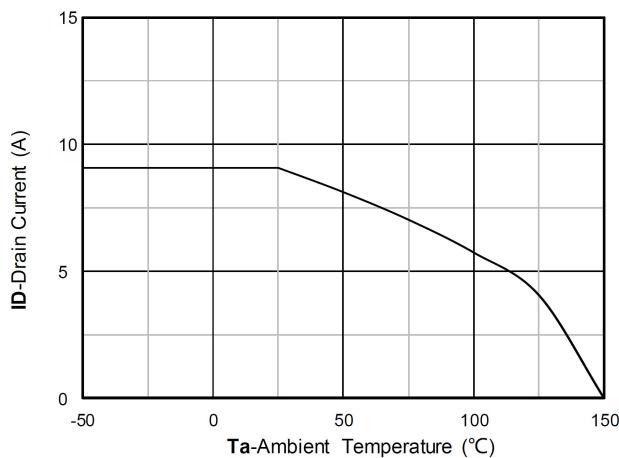
Transfer Characteristics



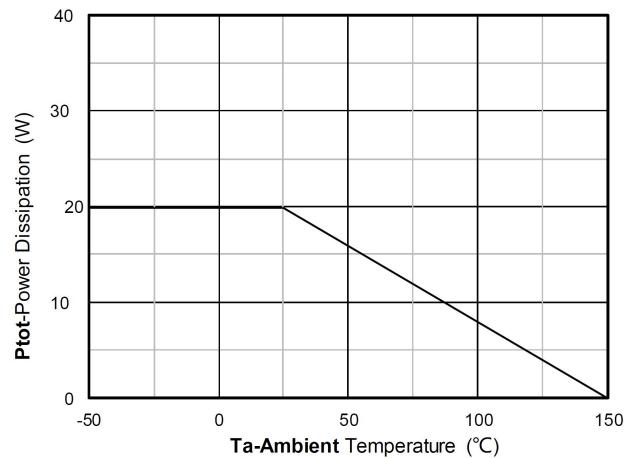
Capacitance Characteristics



Gate Charge



Current dissipation



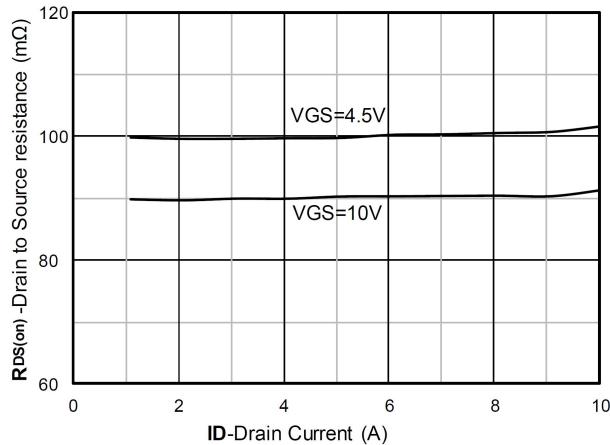
Power dissipation



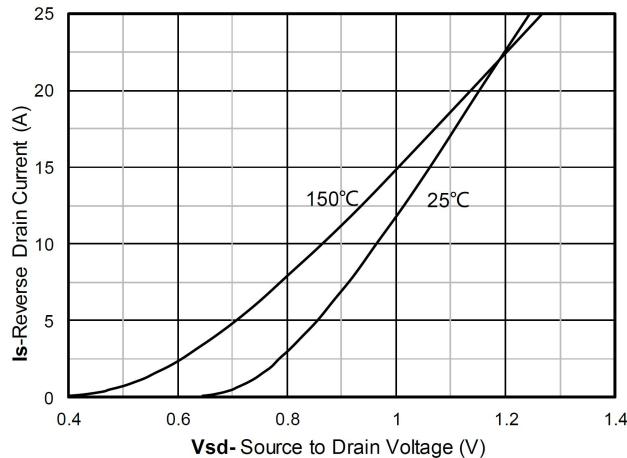
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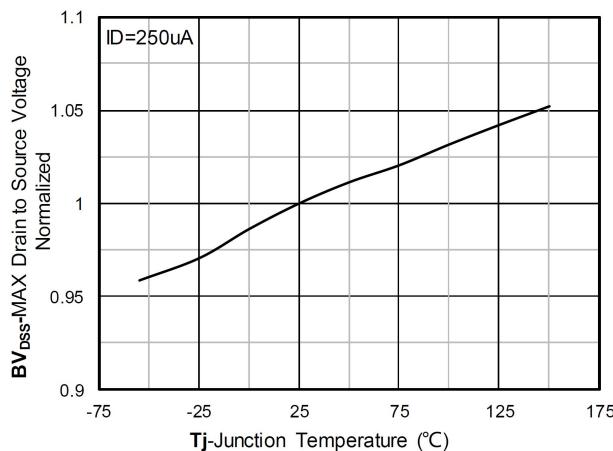
100V Complementary MOSFET



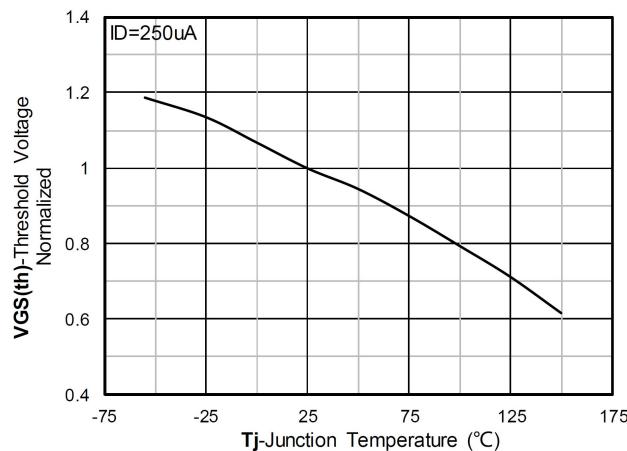
R_{DS(on)} VS Drain Current



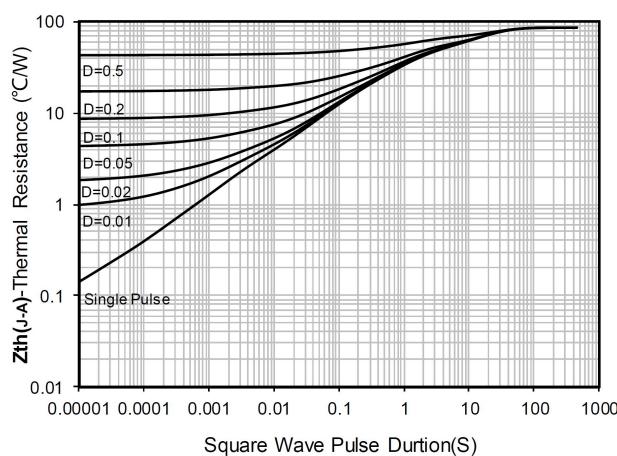
Forward characteristics of reverse diode



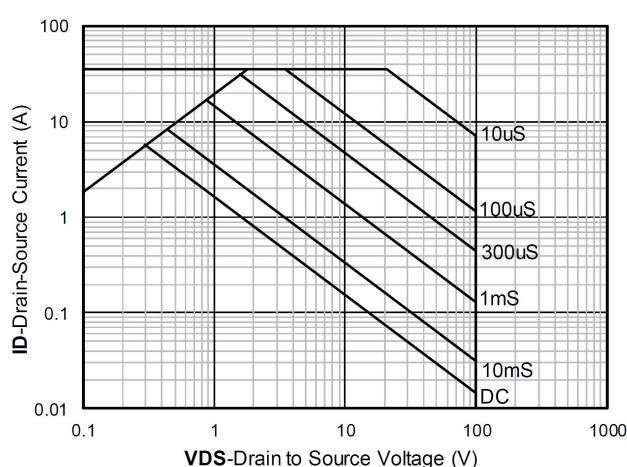
Normalized breakdown voltage



Normalized Threshold voltage



Maximum Transient Thermal Impedance



Safe Operation Area



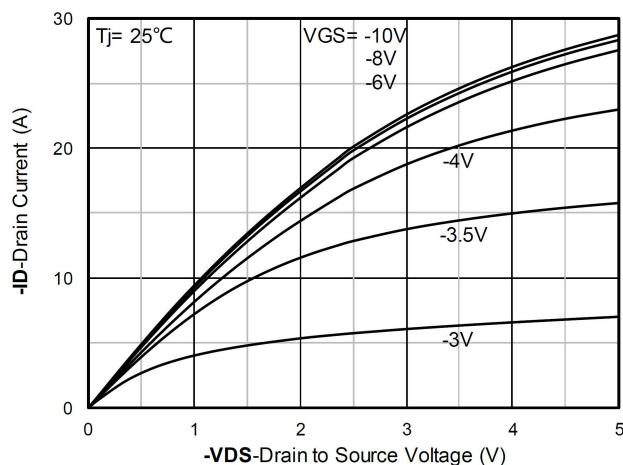
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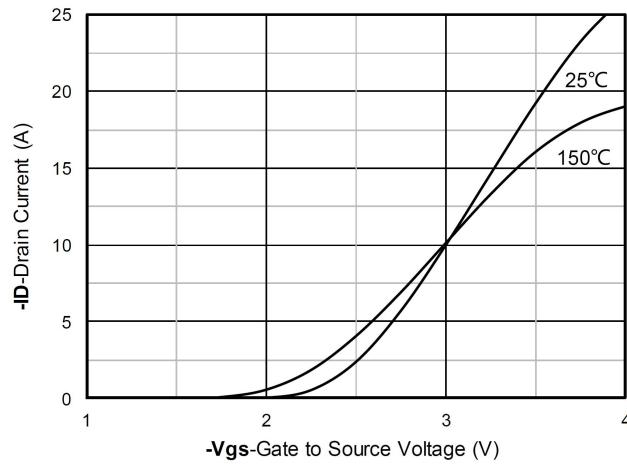
SP1012CNK

100V Complementary MOSFET

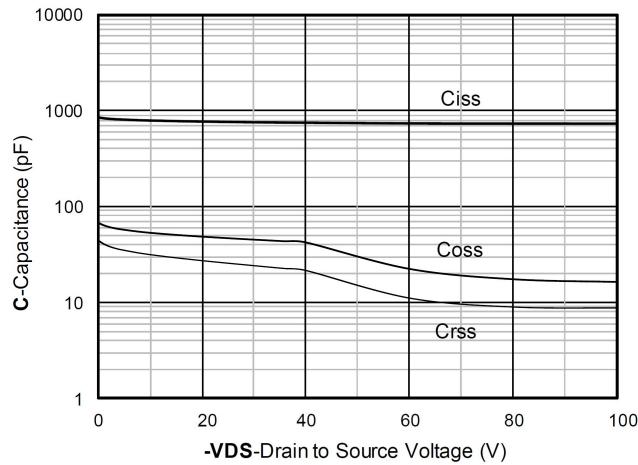
P-Channel Typical Characteristic



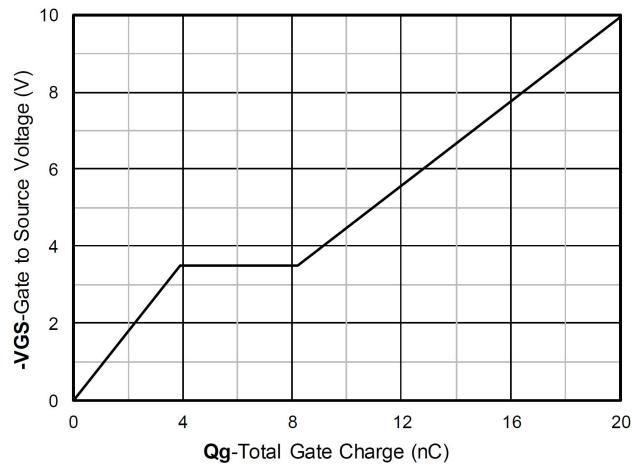
Output Characteristics



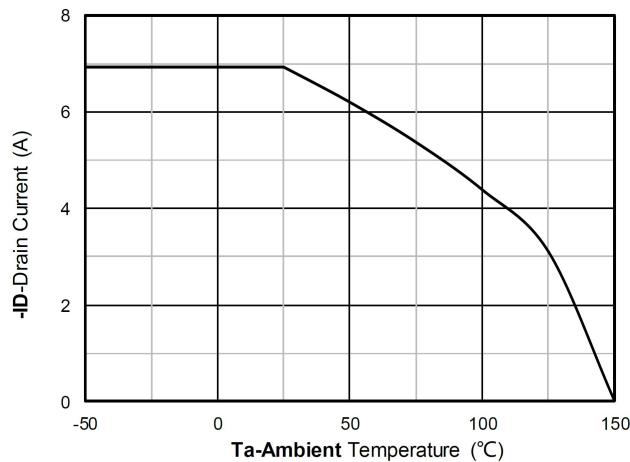
Transfer Characteristics



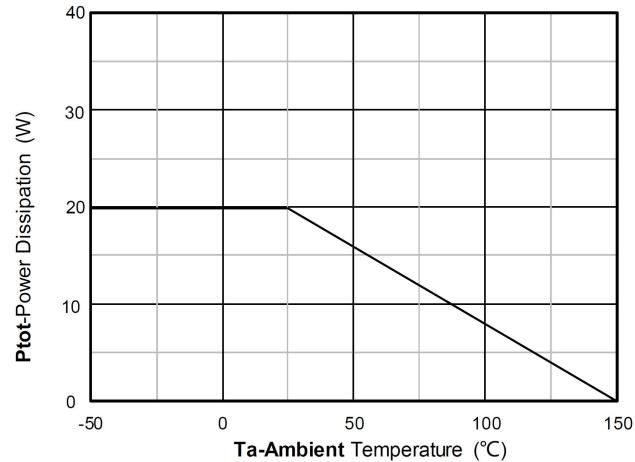
Capacitance Characteristics



Gate Charge



Current dissipation



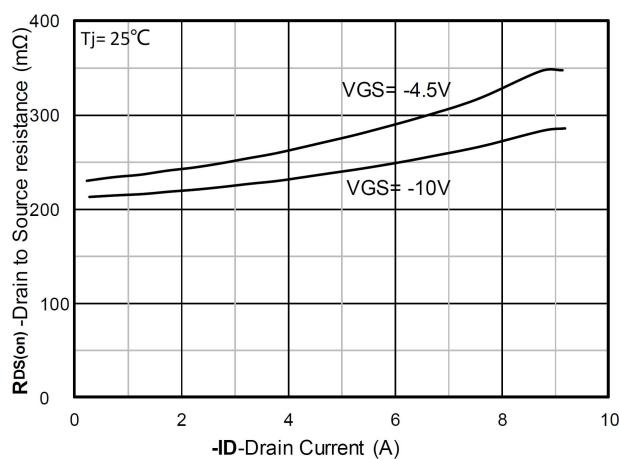
Power dissipation



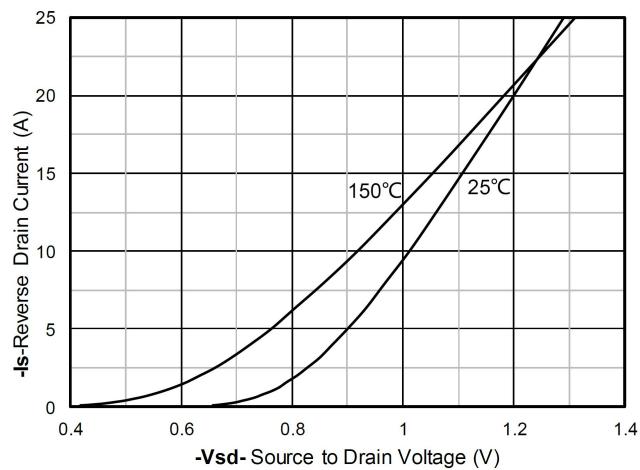
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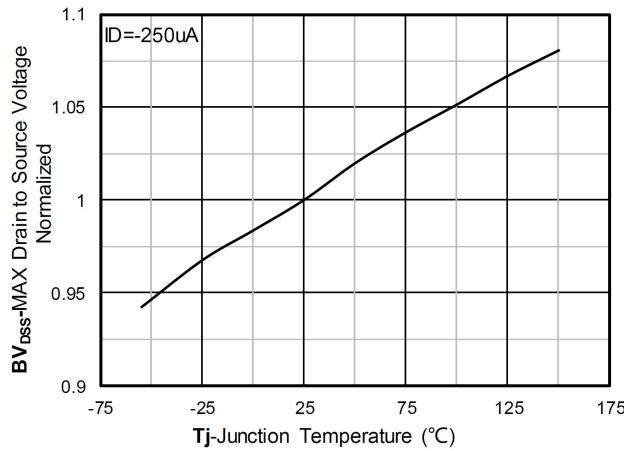
100V Complementary MOSFET



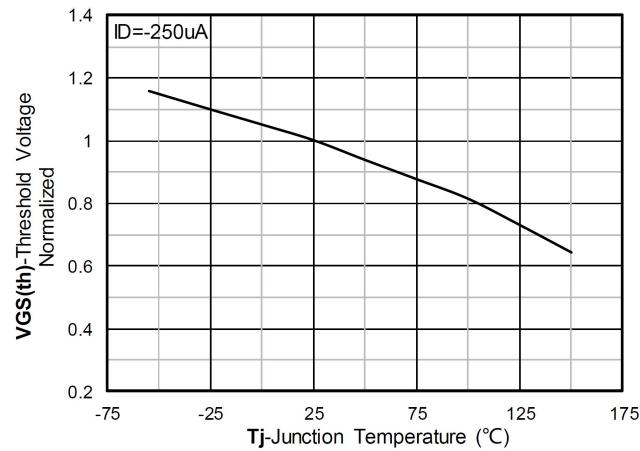
R_{D5(on)} VS Drain Current



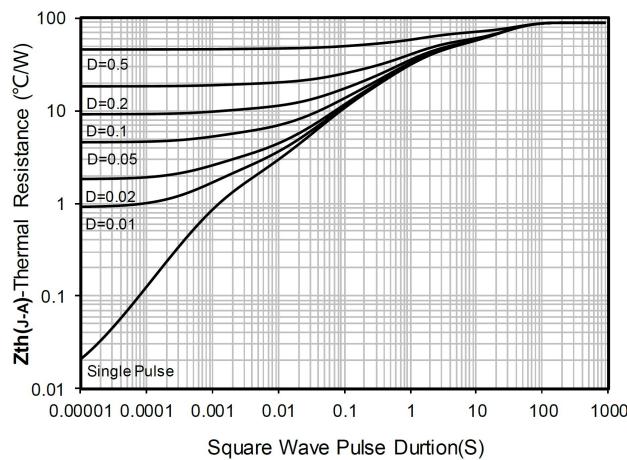
Forward characteristics of reverse diode



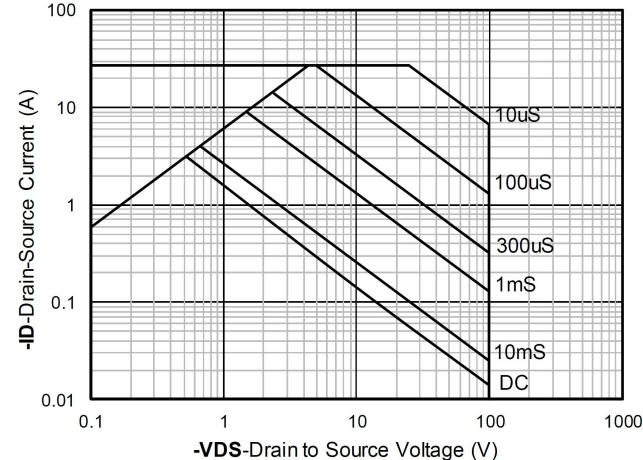
Normalized breakdown voltage



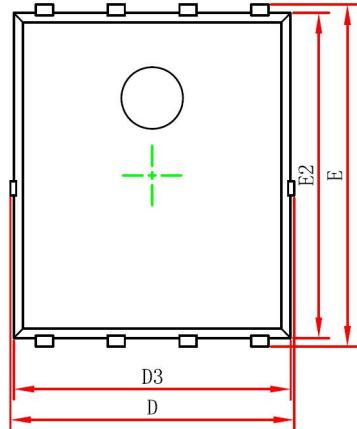
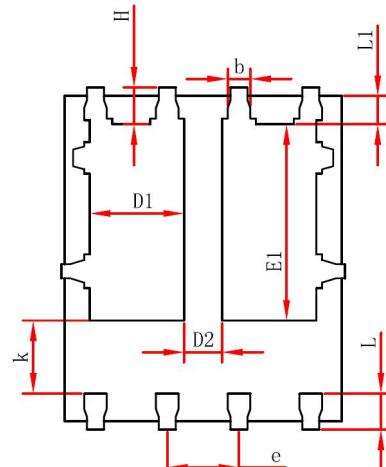
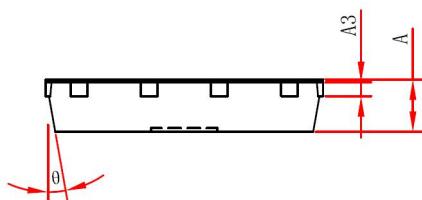
Normalized Threshold voltage



Maximum Transient Thermal Impedance



Safe Operation Area

PDFN5X6-8L Package Information

Top View
 [顶视图]

Bottom View
 [背视图]

Side View
 [侧视图]

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254 REF.			0.010REF.
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	1.470	1.870	0.058	0.074
D2	0.470	0.870	0.019	0.034
E1	3.375	3.575	0.133	0.141
D3	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°